

# Cp E 432: Testing of Computing Systems Electrical and Computer Engineering

Physical defects from semiconductor manufacture, fault modeling and simulation, fault activation and detection in digital systems, digital test pattern synthesis, test coverage, test compaction, online/offline/BIST testing concepts, design-for-test, design-for- manufacture, system testability and diagnosability. 3 Credits

## **Prerequisites**

- El E 351: Electronics Circuits | \$target.descriptions.MinimumGrade\$
- El E 385: Advanced Digital Systems \$target.descriptions.MinimumGrade\$
- El E 386: Advanced Digital Systems Laboratory \$target.descriptions.MinimumGrade\$

# Instruction Type(s)

• Lecture: Lecture for Cp E 432

### **Subject Areas**

• Computer Engineering, General

#### **Related Areas**

Computer Hardware Engineering

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